100V, 40A, 7.7mΩ N-channel Power SGT MOSFET

JMSH1010PU

Features

- $\bullet \quad \text{Excellent $R_{\text{DS(ON)}}$ and Low Gate Charge}$
- 100% UIS Tested
- 100% ΔVds Tested
- Halogen-free; RoHS-compliant

Applications

- Load Switch
- PWM Application
- Power Management

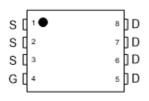
Product Summary

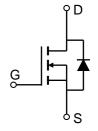
Parameters	Value	Unit
V_{DSS}	100	V
$V_{GS(th)_Typ}$	2.8	V
$I_D(@V_{GS}=10V)$	40	Α
$R_{DS(ON)_Typ}(@V_{GS}=10V$	7.7	mΩ











PDFN3X3-8L

Pin Assignment

Schematic Diagram

Ordering Information

Device	Marking	MSL	Form	Package	Reel(pcs)	Per Carton (pcs)
JMSH1010PU	SH1010P	1	Tape&Reel	PDFN3x3-8L	5000	50000

Absolute Maximum Ratings (@ T_C = 25°C unless otherwise specified)

Symbol	Parameter		Value	Unit
V_{DS}	Drain-to-Source Voltage		100	V
V_{GS}	Gate-to-Source Voltage		±20	V
I-	Continuous Drain Current	$T_C = 25^{\circ}C$	40	A
I _D		$T_C = 100$ °C	25	
I _{DM}	Pulsed Drain Current (1)		Refer to Fig.4	А
E _{AS}	Single Pulsed Avalanche Energy	y ⁽²⁾	165	mJ
P _D	Power Dissipation	$T_C = 25^{\circ}C$	30	W
		$T_C = 100$ °C	12] ^{vv}
T_{J}, T_{STG}	Junction & Storage Temperature R	lange	-55 to 150	°C

Thermal Characteristics

Symbol Parameter		Max	Unit
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient ⁽³⁾	45	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	4.2	C/VV



Electrical Characteristics (T_J = 25°C unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Off Cha	racteristics	l l				
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 80V, V_{GS} = 0V$	-	-	1.0	μА
I _{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA
On Cha	racteristics					
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.9	2.8	3.6	V
R _{DS(ON)}	Static Drain-Source ON-Resistance ⁽⁴⁾	$V_{GS} = 10V, I_D = 20A$	-	7.7	10.0	mΩ
Dynami	c Characteristics					
R_{g}	Gate Resistance	f = 1MHz	-	1.7	-	Ω
C _{iss}	Input Capacitance		1095	1532	2069	pF
C _{oss}	Output Capacitance	$V_{GS} = 0V, V_{DS} = 50V,$ f = 1MHz	459	643	868	pF
C _{rss}	Reverse Transfer Capacitance	1 - 11/11/2	15	21	28	pF
Qg	Total Gate Charge		19	27	36	nC
Q_{gs}	Gate Source Charge	$V_{GS} = 0 \text{ to } 10V$ $V_{DS} = 50V, I_{D} = 20A$	-	7.6	-	nC
Q_{gd}	Gate Drain("Miller") Charge	V _{DS} = 30 V, I _D = 20A	-	8.1	-	nC
0:(-1.:	no Obana daniatia					
	ng Characteristics Turn-On DelayTime	I		44		
t _{d(on)}	, , , , , , , , , , , , , , , , , , ,		-	11		ns
t _r	Turn-On Rise Time	$V_{GS} = 10V, V_{DD} = 50V$	-	21	-	ns
t _{d(off)}	Turn-Off DelayTime	I_{D} = 20A, R_{GEN} = 3.6 Ω	-	23	-	ns
t _f	Turn-Off Fall Time		-	8.8	-	ns
	iode Characteristics	<u> </u>				I .
I _S	laximum Continuous Body Diode Forward Current		-	-	40	Α
I _{SM}	Maximum Pulsed Body Diode Forward Curre		-	-	160	Α
V_{SD}	Body Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 20A$	-		1.2	V
trr	Body Diode Reverse Recovery Time	I _F = 20A, di/dt = 100A/us	32	44	60	ns
Qrr	Body Diode Reverse Recovery Charge	1 20/1, ai/at - 100//us	-	56	-	nC

Notes:

^{1.} Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

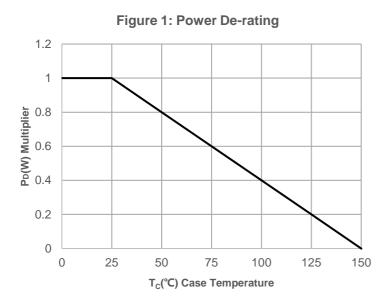
 $^{2.~}E_{AS}~condition:~Starting~T_J=25C,~V_{DD}=50V,~V_G=10V,~R_G=25ohm,~L=3mH,~I_{AS}=10.5A,~V_{DD}=0V~during~time~in~avalanche.$

^{3.} $R_{\theta JA}$ is measured with the device mounted on a 1inch² pad of 2oz copper FR4 PCB.

^{4.} Pulse Test: Pulse Width≤300µs, Duty Cycle≤0.5%.



Typical Performance Characteristics



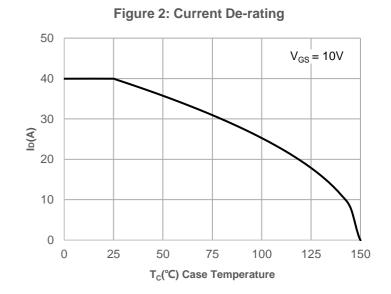
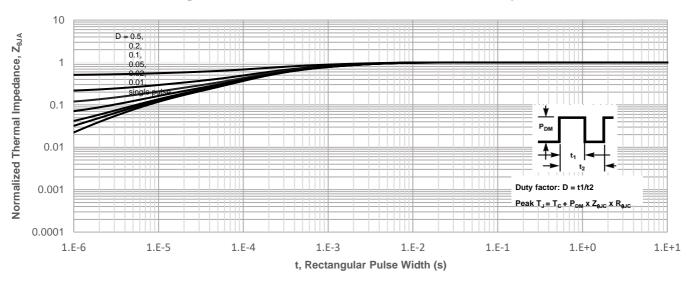


Figure 3: Normalized Maximum Transient Thermal Impedance



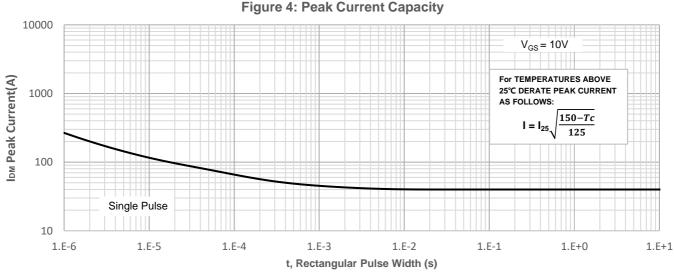


Figure 4: Peak Current Capacity



Typical Performance Characteristics

Figure 5: Output Characteristics

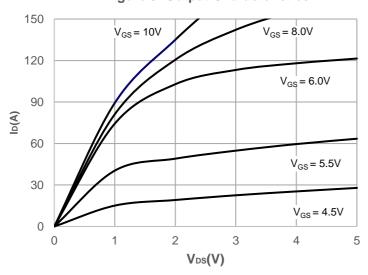


Figure 6: Typical Transfer Characteristics

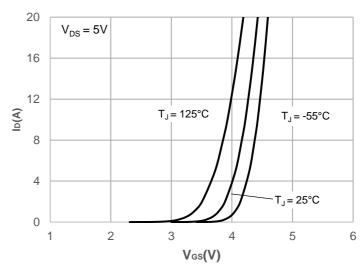


Figure 7: On-resistance vs. Drain Current

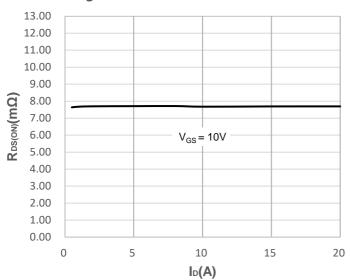


Figure 8: Body Diode Characteristics

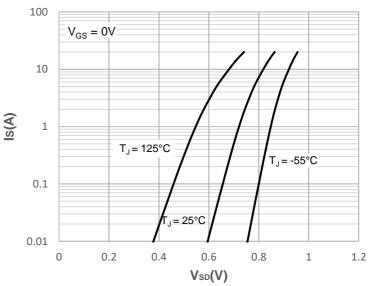


Figure 9: Gate Charge Characteristics

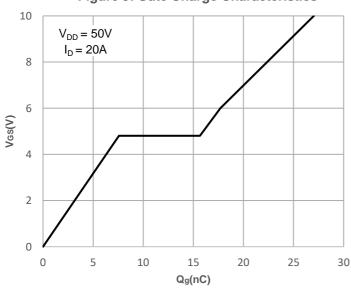
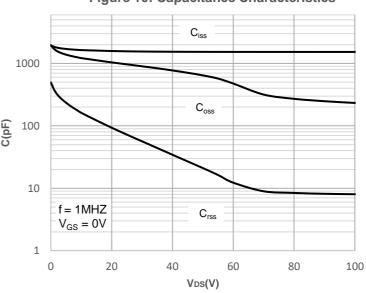


Figure 10: Capacitance Characteristics





Typical Performance Characteristics

Figure 11: Normalized Breakdown voltage vs. Junction Temperature

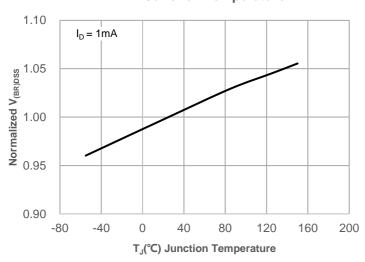


Figure 13: Normalized Threshold Voltage vs. Junction Temperature

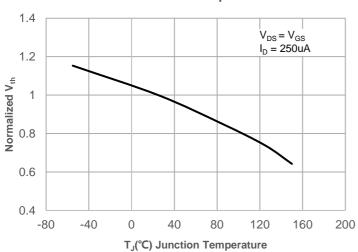


Figure 15: Maximum Safe Operating Area

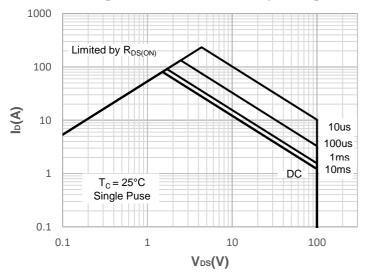
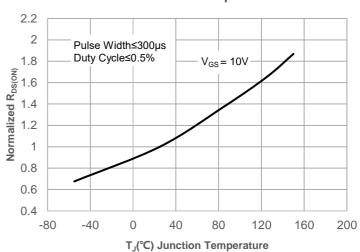
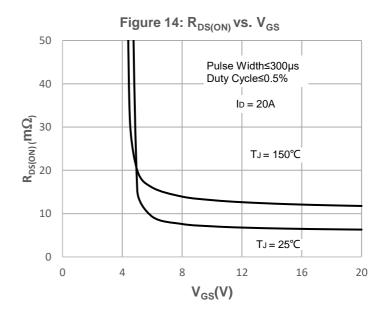


Figure 12: Normalized on Resistance vs. Junction Temperature







Test Circuit

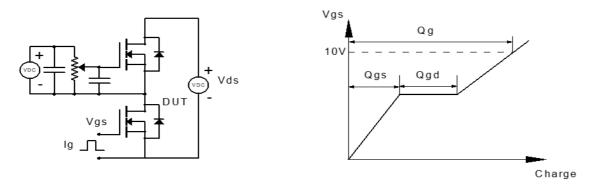


Figure 1: Gate Charge Test Circuit & Waveform

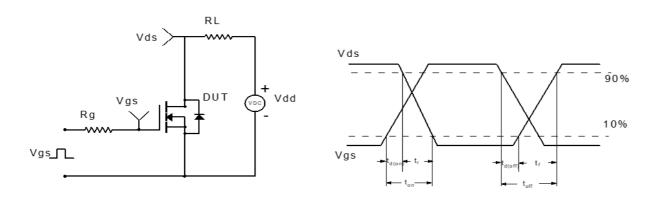


Figure 2: Resistive Switching Test Circuit & Waveform

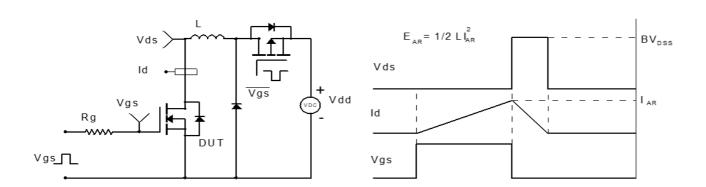


Figure 3: Unclamped Inductive Switching Test Circuit& Waveform

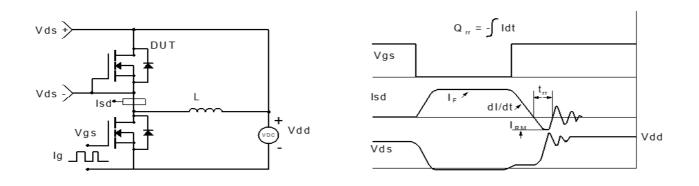
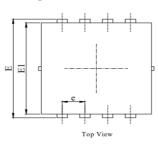
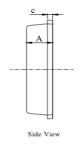


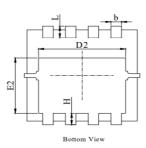
Figure 4: Diode Recovery Test Circuit & Waveform

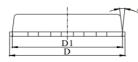


Package Mechanical Data(PDFN3X3-8L)





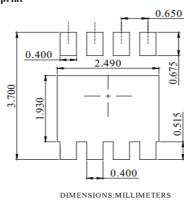




- DIMENSIONING AND TOLERANCING PER ASME
- Y14.5M,1994.
 ALL DIMNESIONS IN MILLIMETER (ANNGLE IN DEGREE).
 DIMENSIONS DI AND EI DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

DIM.	MILLIMETER				
DIM.	MIN.	NOM.	MAX.		
A	0.70	0.75	0.80		
ь	0.25	0.30	0.35		
c	0.10	0.20	0.25		
D	3.00	3.15	3.25		
D1	2.95	3.05	3.15		
D2	2.39	2.49	2.59		
E	3.20	3.30	3.40		
E1	2.95	3.05	3.15		
E2	1.70	1.80	1.90		
e	0.65 BSC				
H	0.30	0.40	0.50		
L	0.25	0.40	0.50		
a			15°		

Recommended Soldering Footprint



Information furnished in this document is believed to be accurate and reliable. However, Jiangsu JieJie Microelectronics Co., Ltd assumes no responsibility for the consequences of use without consideration for such information nor use beyond it. Information mentioned in this document is subject to change without notice, apart from that when an agreement is signed, Jiangsu JieJie complies with the agreement. Products and information provided in this document have no infringement of patents. Jiangsu JieJie assumes no responsibility for any infringement of other rights of third parties which may result from the use of such products and information.



is a registered trademark of Jiangsu JieJie Microelectronics Co.,Ltd.